

Multi75DLC

AFM Tip

SHAPE	HEIGHT	SETBACK	RADIUS	HALF CONE ANGLE
Rotated	17 μm (15 – 19 μm)*	15 μm (10 – 20 μm)*	15 nm	20°–25° along cantilever axis, 25°–30° from side, 10° at the apex

AFM Cantilever

Cantilever A	
Shape	Beam
Force Constant	3 N/m (1 – 7 N/m)*
Resonance Frequency	75 kHz (60 – 90 kHz)*
Length	225 μm (215 – 235 μm)*
Width	28 μm (23 – 33 μm)*
Thickness	3 μm (2 – 4 μm)*

* typical range

Coating

Diamond–Like–Carbon coating on tip side of the cantilever, 15nm thick;Aluminum coating on detector side of the cantilever, 30 nm thick

Alignment Grooves

This product features alignment grooves on the back side of the holder chip.

Additional Info

Monolithic silicon AFM probe for force modulation and pulsed force mode (PFM).

High durability and hydrophobicity due to **Diamond–Like–Carbon coating** on tip side of the AFM cantilever.

The rotated AFM tip allows for more symmetric representation of high sample features. The consistent AFM tip radius ensures good resolution and reproducibility.

The AFM holder chip fits most commercial AFM systems as it is industry standard size.